序号	试验项目 (Test Item)	试验条件 (Condition)	抽样数 (Sample size)	判定标准 (Decision)	试验依据 (Reference)
		[illegible]			
er≤USL	IEC 60747	1	高温反偏 (High Temperature Reverse Bias)	b、Time: 168h/1000h; c、Temperature: Fast Recovery Diode or Thyristor: 125℃; Discrete Device,MOSFET or IGBT: 145℃; Rectifier Diode: 150℃.	5PCS (FG)	LSL≤Electrical Paramet
ical Parameter≤USL	IEC 60747	2	(High Temperature Grating Bias)	c、Time: 168h/1000h.	5PCS (FG)	LSL≤Electr
le Times: 10Times/100Times.	IEC 60068-2-14	温度循环	a、Temperature: Low Temperature -55℃ for 30min; High Temperature 150℃ for 30min;			c、Cyc
perature: 85℃; idity: 85% RH; e: 168h/1000h.	5PCS (FG)	LSL≤Electrical Parameter≤USL	IEC 60068-2-67	4	恒温恒湿 (Constant Temperature and Humidity)	a、Temp b、Hum c、Tim
[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]
高温存储 (High Temperature Storage)	a、Temperature: T_{stgmax}; b、Time: 168H/1000H.	5PCS (FG)	LSL≤Electrical Parameter≤USL	IEC 60068-2-2	6	(
低温存储 (Low Temperature storage)	a、Temperature: T_{stgmin}; b、Time: 168H/1000H.	5PCS (FG)	LSL≤Electrical Parameter≤USL	IEC 60068-2-1	7	(
冲击试验 (Shock Test)	a、Max.: 50G; b、Pulse Time: 6ms,Sine Half Wave; 18Times in total.	5PCS (FG)	LSL≤Electrical Parameter≤USL	IEC 60068-2-27	8	
5PCS (FG)	LSL≤Electrical Parameter≤USL	9	振动试验 (Vibration Test)	a、Vibration Waveform: 5~200 Hz,Sine Wave; b、Direction of Vibration: X, Y, Z; d、Vibration Time (Frequency Sweep: 5Hz~200Hz~5Hz, Trip, 24 per cycle		